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AO4484

40V N-Channel MOSFET

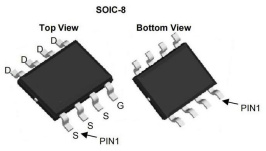
General Description

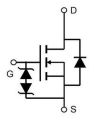
The AO4484 uses advanced trench technology to provide excellent $R_{DS(ON)}$ with low gate charge. This is an all purpose device that is suitable for use in a wide range of power conversion applications.

Product Summary

V_{DS} (V) = 40V
I_D = 10A (V_{GS} = 10V)
$R_{DS(ON)}$ < 10mΩ (V_{GS} = 10V)
$R_{DS(ON)}$ < 12mΩ (V_{GS} = 4.5V)

100% UIS Tested
100% Rg Tested





Orderable Part Number	Package Type	Form	Minimum Order Quantity
	SO-8	Tape & Reel	3000

Absolute Maximum Ratings T_J=25℃ unless otherwise noted

Parameter		Symbol	10 Sec	Steady State	Units
Drain-Source Voltage		V_{DS}	40		V
Gate-Source Voltage		V_{GS}	±20		V
Continuous Drain Current [A]	T_A=25℃	I_D	13.5	10	A
	T_A=70℃		10.8	8	
Pulsed Drain Current [B]		I_{DM}	120		
Avalanche Current [G]		I_{AR}	23		
Repetitive avalanche energy L=0.3mH [G]		E_{AR}	79		mJ
Power Dissipation [A]	T_A=25℃	P_D	3.1	1.7	W
	T_A=70℃		2.0	1.1	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150		℃

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	31	40	℃/W
Maximum Junction-to-Ambient [A]	Steady State		59	75	℃/W
Maximum Junction-to-Lead [C]	Steady State	$R_{\theta JL}$	16	24	℃/W

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Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D = 250μA, V_{GS} = 0V	40			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 40V, V_{GS} = 0V			1	μA
		T_J = 55℃			5	
I_{GSS}	Gate-Body leakage current	V_{DS} = 0V, V_{GS} = ±20V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS} I_D = 250μA	1.7	2.2	3	V
$I_{D(ON)}$	On state drain current	V_{GS} = 10V, V_{DS} = 5V	120			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS} = 10V, I_D = 10A		8.2	10	mΩ
		T_J=125℃		12.5	16	
		V_{GS} = 4.5V, I_D = 8A		10	12.5	
g_{FS}	Forward Transconductance	V_{DS} = 5V, I_D = 10A		75		S
V_{SD}	Diode Forward Voltage	I_S = 1A,V_{GS} = 0V		0.72	1	V
I_S	Maximum Body-Diode Continuous Current				2.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=20V, f=1MHz		1500	1950	pF
C_{oss}	Output Capacitance			215		pF
C_{rss}	Reverse Transfer Capacitance			135		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	2	3.5	5	Ω
SWITCHING PARAMETERS						
Q_g (10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=20V, I_D=10A		27.2	37	nC
Q_g (4.5V)	Total Gate Charge			13.6	18	nC
Q_{gs}	Gate Source Charge			4.5		nC
Q_{gd}	Gate Drain Charge			6.4		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=20V, R_L= 2Ω, R_{GEN}=3Ω		6.4		ns
t_r	Turn-On Rise Time			17.2		ns
$t_{D(off)}$	Turn-Off DelayTime			29.6		ns
t_f	Turn-Off Fall Time			16.8		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=10A, dI/dt=100A/μs		30	40	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=10A, dI/dt=100A/μs		19		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A = 25℃. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using t ≤ 300μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25℃. The SOA

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

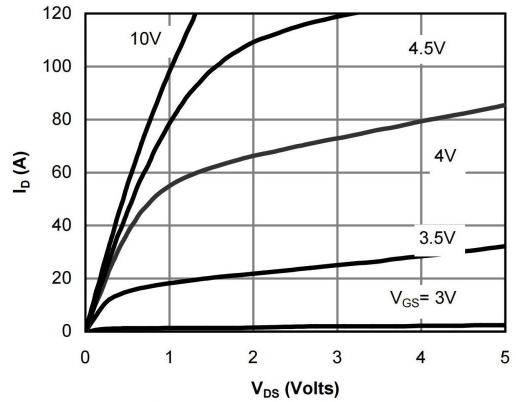


Figure 1: On-Region Characteristics

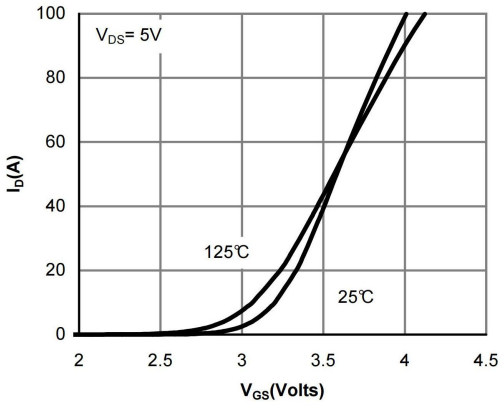


Figure 2: Transfer Characteristics

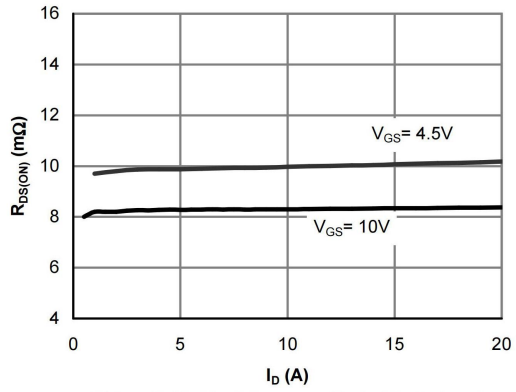


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

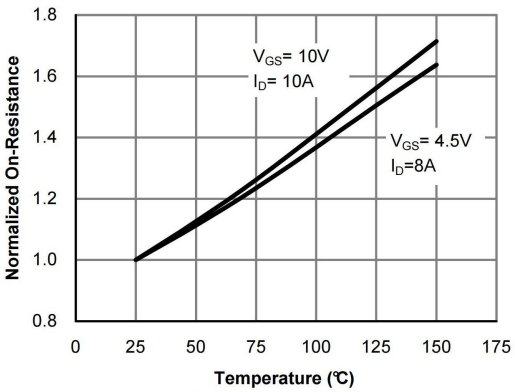


Figure 4: On-Resistance vs. Junction Temperature

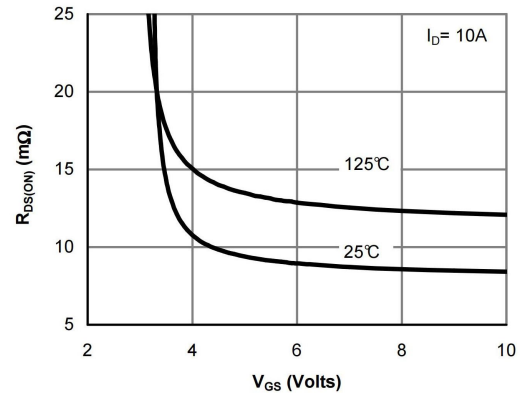


Figure 5: On-Resistance vs. Gate-Source Voltage

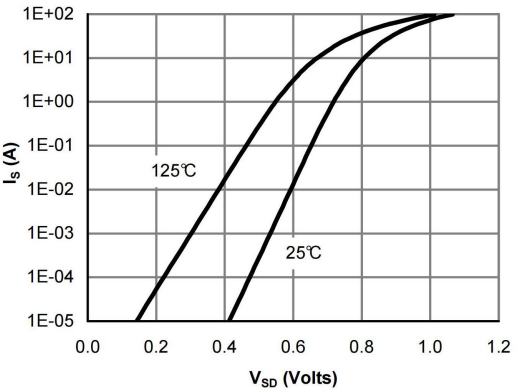


Figure 6: Body-Diode Characteristics

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

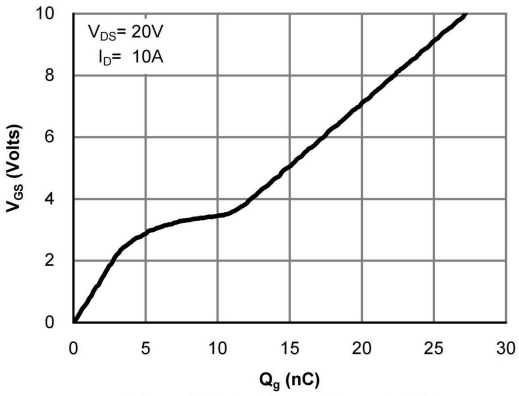


Figure 7: Gate-Charge Characteristics

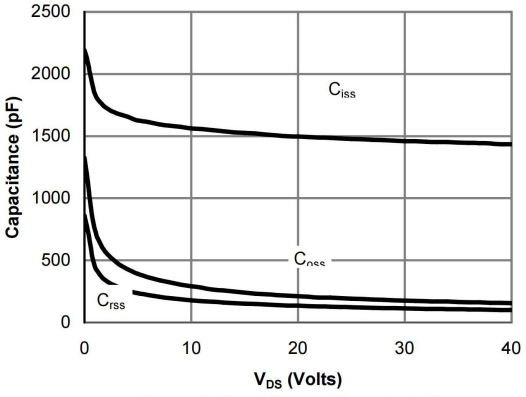


Figure 8: Capacitance Characteristics

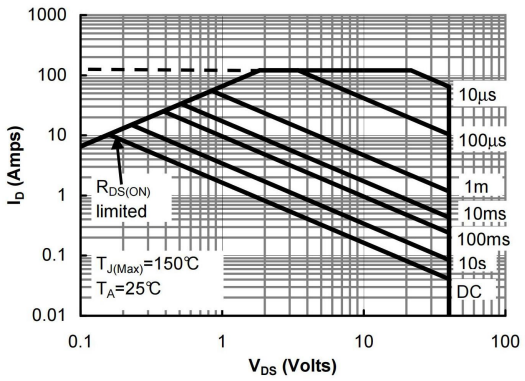


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

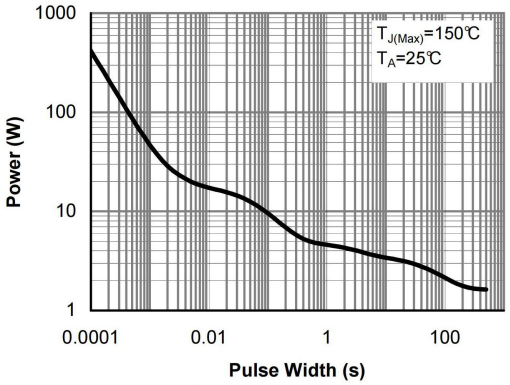


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

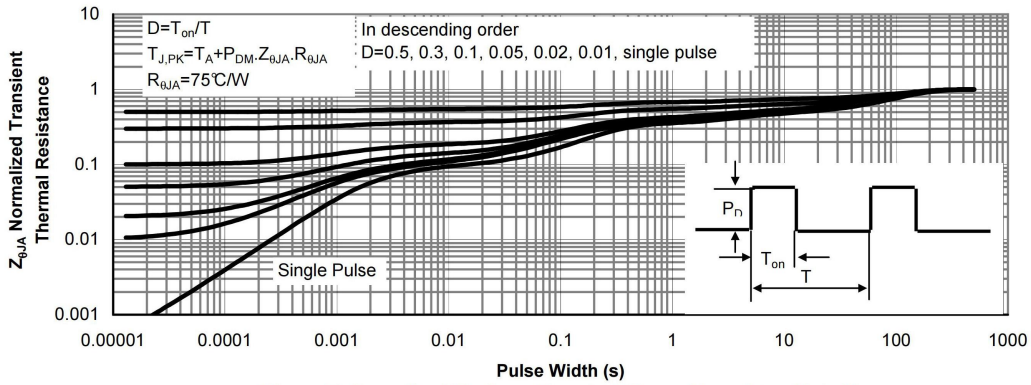
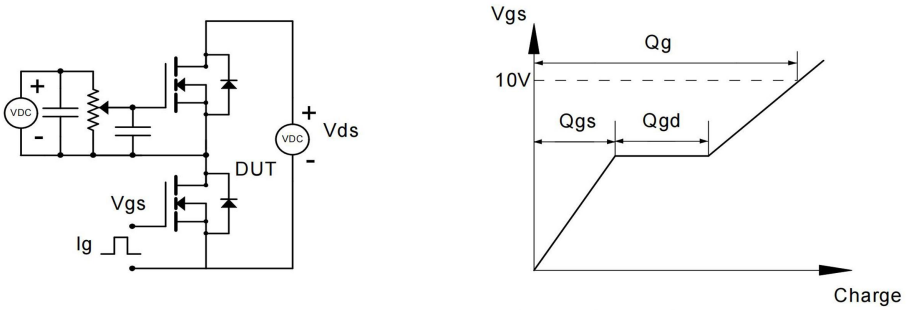


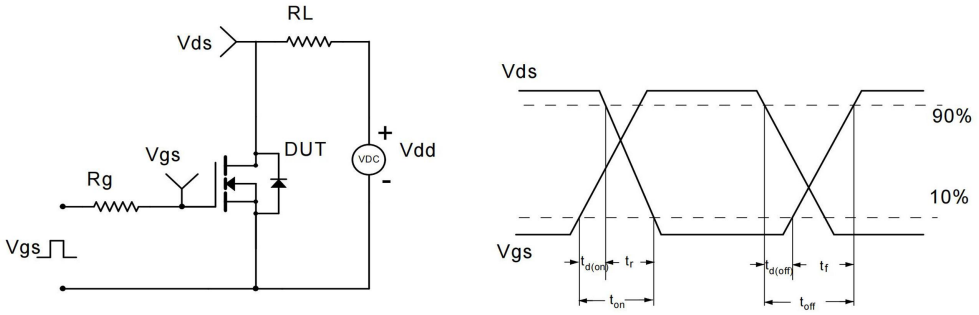
Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)

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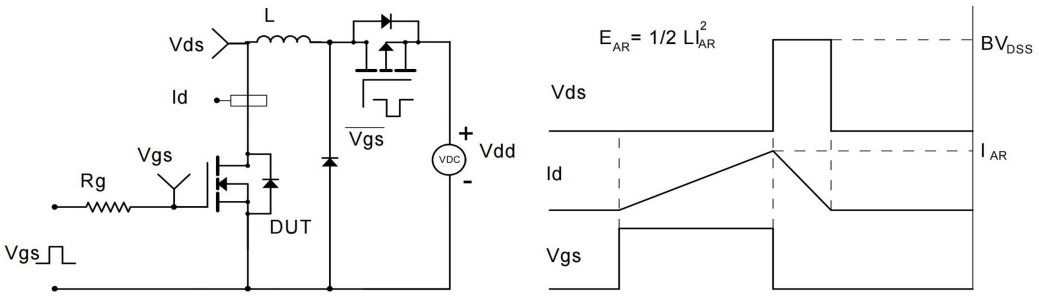
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

